

**Notice of References Cited**Application/Control No.  
**09/682,443**Applicant(s)/Patent Under Reexam  
**Michiel Jacques Van Nieuwstadt**Examiner  
**Tu M. Nguyen**Art Unit  
**3748**

Page 1 of 1

**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
A	5,806,310	9/1998	Daidou et al.	60	286
B	6,182,443	2/2001	Jarvis et al.	60	274
C	6,209,313	4/2001	Wissler et al.	60	286
D	6,311,484	11/2001	Roth et al.	60	286
E					
F					
G					
H					
I					
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Country</b>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
N						
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	<b>Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages</b>
U	
V	
W	
X	

If any of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.